

# HiPerFET™ **Power MOSFET**

# **IXFN170N10 IXFK170N10**

$\mathbf{V}_{\mathtt{DSS}}$	I <sub>D25</sub>	R <sub>DS(on)</sub>	t <sub>rr</sub>	
100V	170A	10m $\Omega$	200ns	
100V	170A	$10 \mathrm{m}\Omega$	200ns	

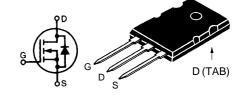
# Single MOSFET Die

Preliminary data

Symbol	Test Conditions		Maximu IXFK 170N10			
V <sub>DSS</sub>	T <sub>1</sub> = 25°C to 150°	С	100	10	00	V
V <sub>DGR</sub> ①	$T_{J}^{3} = 25^{\circ}\text{C to } 150^{\circ}$		100	10	00	V
V <sub>GS</sub>	Continuous		±20	±2	20	V
V <sub>GSM</sub>	Transient		±30	±3	30	V
I <sub>D25</sub>	$T_c = 25^{\circ}C$		170③	17	70	Α
<b>I</b> <sub>D125</sub> 4	$T_{c}^{\circ} = 125^{\circ}C$		76	N	Α	
I <sub>DM</sub> ②	$T_{c}^{\circ} = 25^{\circ}C$		680	68	30	Α
I <sub>AR</sub>	$T_{c} = 25^{\circ}C$		170	17	70	Α
E <sub>AR</sub>	T <sub>C</sub> = 25°C		60	6	0	mJ
dv/dt	$I_{S} \leq I_{DM}$ , di/dt $\leq 10$ $T_{J} \leq 150$ °C, $R_{G} =$	$0 \text{ A/}\mu\text{s}, \text{ V}_{\text{DD}} \leq \text{V}_{\text{DSS}}$ $2 \Omega$	5	5 V/ns		V/ns
P <sub>D</sub>	$P_{\rm D}$ $T_{\rm C} = 25^{\circ} \rm C$		560	560 600 V		
T,			-55	+150°C		
T <sub>JM</sub>			15	50		°C
T <sub>stg</sub>			-55 +150°C			
T <sub>L</sub>	1.6 mm (0.063 in)	from case for 10 s	300	N/A		°C
V <sub>ISOL</sub>	50/60 Hz, RMS	t = 1 min	N/A	2500		V~
	$I_{ISOL} \le 1 \text{ mA}$	t = 1 s	N/A	3000		V~
M <sub>d</sub>	Mounting torque		0.9/6	1.5/13	Nm	/lb.in.
u	Terminal connection	on torque	N/A	1.5/13	Nm	/lb.in.
Weight			10	30		g

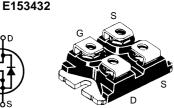
<b>Symbo</b> (T <sub>J</sub> = 25	Test Conditions °C, unless otherwise specified)	Min.	Characte Typ.	eristic \   Max.	/alues
V <sub>DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 3\text{mA}$ $V_{DSS}$ temperature coefficient	100	0.077		V %/K
V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 8mA$ $V_{GS(th)}$ temperature coefficient	2	-0.183	4	V %/K
I <sub>GSS</sub>	$V_{GS} = \pm 20 V, V_{GS} = 0 V$			±200	nA
I <sub>DSS</sub>	V <sub>DS</sub> = 0.8 • V <sub>DSS</sub> V V <sub>GS</sub> = 0 V	$T_J = 25^{\circ}C$ $T_J = 125^{\circ}C$		400 2	μA mA
R <sub>DS(on)</sub>	$V_{GS}$ = 10 V, $I_D$ = 0.5 • $I_{D25}$ Pulse test, t ≤ 300 ms, duty cycle d ≤ 2 %			10	mΩ

#### **TO-264 AA (IXFK)**



miniBLOC, SOT-227 B (IXFN)





G = Gate D = DrainS = Source TAB = Drain

Either Source terminal at miniBLOC can be used as Main or Kelvin Source

#### **Features**

- International standard packages
- Encapsulating epoxy meets UL94V-0, flammability classification
- miniBLOC with Aluminium nitride isolation
- $\bullet \ \mathsf{Low} \ \mathsf{R}_{\mathsf{DS} \, \mathsf{(on)}} \ \mathsf{HDMOS^{\mathsf{TM}}} \ \mathsf{process}$
- Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS)
- Low package inductance
- · Fast intrinsic Rectifier

#### **Applications**

- DC-DC converters
- · Synchronous rectification
- Battery chargers
- Switched-mode and resonant-mode power supplies
- · DC choppers
- Temperature and lighting controls
- · Low voltage relays

#### **Advantages**

- · Easy to mount
- · Space savings
- · High power density

IXYS reserves the right to change limits, test conditions, and dimensions.

97505D (7/00)



SymbolTest ConditionsCh $(T_1 = 25^{\circ}C, unless otherwise specified)$ Min.			naracteristic Values Typ.   Max.		
g <sub>fs</sub>	$V_{DS} = 10 \text{ V}; I_{D} = 0.5 \cdot I_{D25}, \text{ pulse test}$	65	S		
C <sub>iss</sub>		10,300	pF		
C <sub>oss</sub>	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	2,200	pF		
$\mathbf{C}_{rss}$		1,200	pF		
t <sub>d(on)</sub>		40	ns		
t <sub>r</sub>	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_{D} = 0.5 \cdot I_{D25}$	90	ns		
t <sub>d(off)</sub>	$R_{\rm G} = 1 \Omega$ (External),	158	ns		
t <sub>f</sub>	J	79	ns		
Q <sub>g(on)</sub>		515	nC		
$\mathbf{Q}_{gs}$	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_{D} = 0.5 \cdot I_{D25}$	62	nC		
$\mathbf{Q}_{gd}$		276	nC		
R <sub>thJC</sub>	TO-264 AA		0.22 K/W		
R <sub>thCK</sub>	TO-264 AA	0.15	K/W		
$R_{thJC}$	miniBLOC, SOT-227 B		0.21 K/W		
R <sub>thCK</sub>	miniBLOC, SOT-227 B	0.05	K/W		

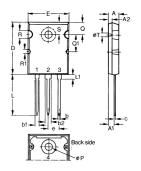
#### Source-Drain Diode

$(T_J = 25^{\circ}C, \text{ unless otherwise specified})$		Ch	haracteristic Values		
Symbol	Test Conditions Mi	n.	Тур.	Max.	
I <sub>s</sub>	$V_{GS} = 0$			170	Α
I <sub>sm</sub>	Repetitive; pulse width limited by T <sub>JM</sub>			680	A
V <sub>SD</sub>	$I_F = 100 \text{ A}, V_{GS} = 0 \text{ V},$ Pulse test, t $\leq$ 300 $\mu$ s, duty cycle d $\leq$ 2 %			1.5	V
t <sub>rr</sub> Q <sub>RM</sub> I <sub>RM</sub>			175 1.1 12.6		ns μC Α

Notes:

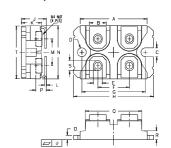
- 1.  $R_{GS}$  = 1 M $\Omega$ 2. Pulse width limited by  $T_{JM}$ .
- 3. Chip capability
- 4. Current limited by external leads

### **TO-264 AA Outline**



Dim.	Millimeter		Inches		
	Min.	Max.	Min.	Max.	
Α	4.82	5.13	.190	.202	
A1	2.54	2.89	.100	.114	
A2	2.00	2.10	.079	.083	
b	1.12	1.42	.044	.056	
b1	2.39	2.69	.094	.106	
b2	2.90	3.09	.114	.122	
С	0.53	0.83	.021	.033	
D	25.91	26.16	1.020	1.030	
Е	19.81	19.96	.780	.786	
е	5.46 BSC		.215 BSC		
J	0.00	0.25	.000	.010	
K	0.00	0.25	.000	.010	
L	20.32	20.83	.800	.820	
L1	2.29	2.59	.090	.102	
Р	3.17	3.66	.125	.144	
Q	6.07	6.27	.239	.247	
Q1	8.38	8.69	.330	.342	
R	3.81	4.32	.150	.170	
R1	1.78	2.29	.070	.090	
S	6.04	6.30	.238	.248	
T	1.57	1.83	.062	.072	

### miniBLOC, SOT-227 B



M4 screws (4x) supplied

Dim.	Millir	neter	Inches		
	Min.	Max.	Min.	Max.	
Α	31.50	31.88	1.240	1.255	
В	7.80	8.20	0.307	0.323	
С	4.09	4.29	0.161	0.169	
D	4.09	4.29	0.161	0.169	
Е	4.09	4.29	0.161	0.169	
F	14.91	15.11	0.587	0.595	
G	30.12	30.30	1.186	1.193	
Ι	38.00	38.23	1.496	1.505	
J	11.68	12.22	0.460	0.481	
K	8.92	9.60	0.351	0.378	
L	0.76	0.84	0.030	0.033	
М	12.60	12.85	0.496	0.506	
N	25.15	25.42	0.990	1.001	
0	1.98	2.13	0.078	0.084	
Р	4.95	5.97	0.195	0.235	
Q	26.54	26.90	1.045	1.059	
R	3.94	4.42	0.155	0.174	
S	4.72	4.85	0.186	0.191	
Т	24.59	25.07	0.968	0.987	
U	-0.05	0.1	-0.002	0.004	



Figure 1. Output Characteristics at 25°C

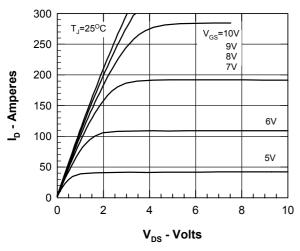


Figure 3.  $R_{\rm DS(on)}$  normalized to 0.5  $I_{\rm D25}$  value vs.  $I_{\rm D}$ 

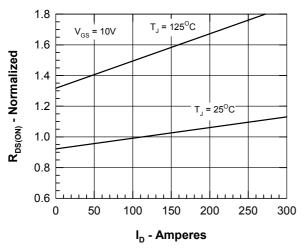


Figure 5. Drain Current vs. Case Temperature

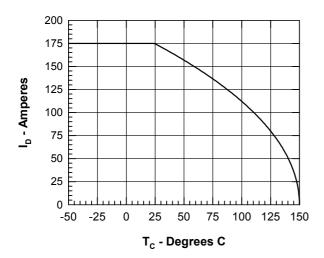


Figure 2. Output Characteristics at 125°C

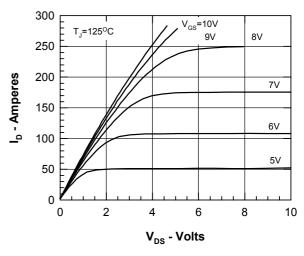


Figure 4.  $\rm R_{DS(on)}$  normalized to 0.5  $\rm I_{D25}~$  value vs.  $\rm T_{J}$ 

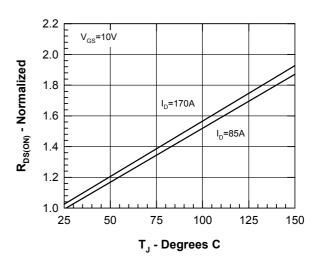


Figure 6. Admittance Curves

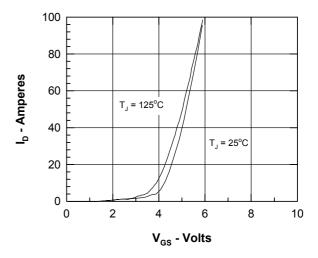




Figure 7. Gate Charge

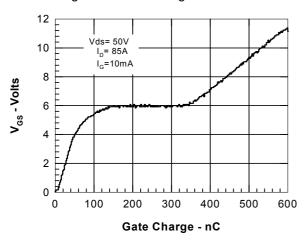


Figure 8. Capacitance Curves

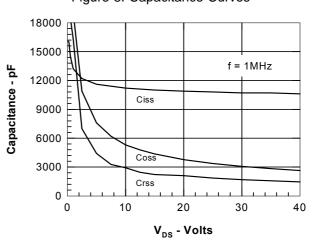
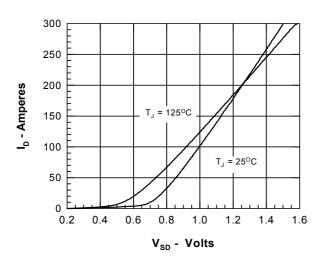


Figure 9. Forward Voltage Drop of the Intrinsic Diode





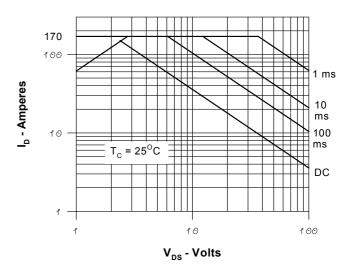
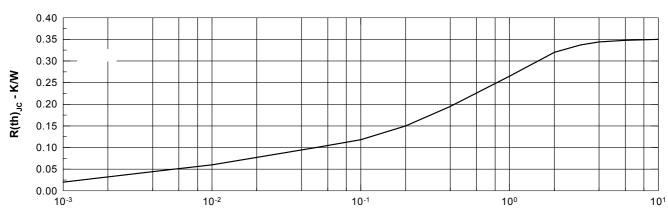


Figure 11. Transient Thermal Resistance



**Pulse Width - Seconds**